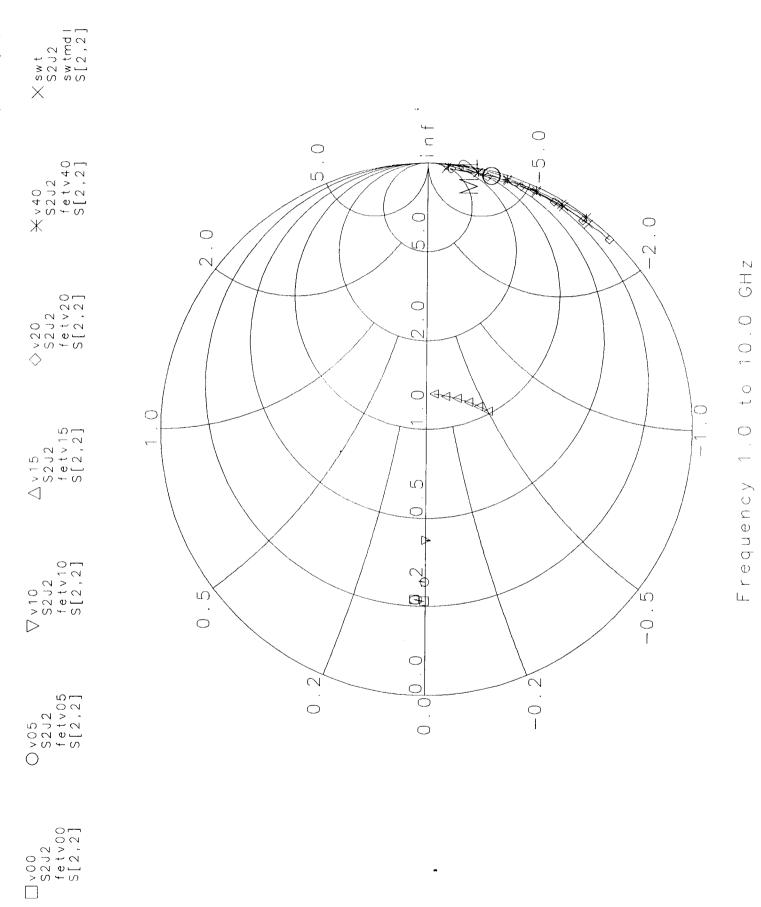
FALL 1996 EE787 MMIC Design Johns Hopkins University <u>Measurement Results</u> Craig Moore and John Penn

Attached are the measurements from the Fall 1996 MMIC Design Course of Johns Hopkins University. The designs were implemented in Fall of 1996 and were fabricated by TriQuint in the summer of 1997. Measurements were made in late 1997 and early 1998. Overall the designs were very successful. Unfortunately measurements for the RF T/R Switch were not available when these results were compiled. I understand that the device was successfully tested up to 1 Watt but I expect the results at a later date. Craig Moore and I did measure an individual probable FET on that particular part and found that an approximate first cut model for an "ON" 300 um FET is 10.8 ohms and "OFF" is about 110 fF. This is pretty close to the old HA switch model but the pinchoff appears to be a around -1.8V to -1.9V rather than the usual -1.5V. Attached is a smith chart plot of the switch at various biases from 0.0V to -4.0V. The name "fetvXY" implies a bias voltage of -X.Y Volts, i.e. fetv15 is the measurement at -1.5V. Also, attached are some plots of the die attaches from the power devices that were attached to kovar to act as a heat sink. We were able to probe 2 different designs up to 1/2 Watt of output and I think we were limited by our input driver not the devices. Still we were pretty happy with 1/2 Watt since that was our goal for the designs. The kovar heat sink improved the measurements even small signal for the 2 power designs considerably.

Thanks to Gary Wray of HPEEsof particularly for his excellent library development and to all of TriQuint and HPEEsof for all the support.

John E. Penn Craig Moore JHU EE 787 MMIC Design



.

VCO Testing Fall 96 MMIC Projects

The VCO consists of a FET with tuning diodes to create an ocsillator, and a buffer amplifier to provide output matching and additional gain to achieve sufficient output power.

Bias Inputs: 1) +5V to Buffer Amp

- 2) +5V to VCO FET
- 3) Control Voltage for VCO
- 4) VG to set Bias for Buffer Amp

1) Because of the layout, the VCO can be tested without biasing the buffer amp. The probe station and a spectrum analzyer were used for the initial test. The device drew about 44 mA at +5V (IDSS bias). It oscillated at about 2.366 Ghz but was not tuneable. Turns out the diodes were in parallel with an inductor which essentially shorts out the bias dropping the entire bias voltage across the 100 ohm resistor to the bias. Tried breaking the airbridge inductor but still could not be tuned. The oscillation frequency did change however to about 2.44 Ghz. The oscillation was also sensitive to drain bias and shifted somewhat by varying the supply from +2V to +5V. Output power likewise changed from +3 dBM to +10 dBM. Cable losses and probe losses were not measured but were probably about 2 dB (i.e. add about 2 dB to measurements for actual power out). Essentially the VCO had the desired output power without the need for the buffer amp. The student was interested in redoing the design to fix the shorted out biasing scheme.

2) Broke airbridge from VCO to output pad to test buffer amp. Initially oscillated at 50Mhz but this was damped out by some capacitance at the DC bias probes. Amp bias was controllable and was set to about 20-40% IDSS at +5V but the only signal on the spectrum analyzer was -50dBm at about 4 Ghz. It appears that the biasing of the buffer amp may have changed the match to the VCO such that it no longer oscillated.

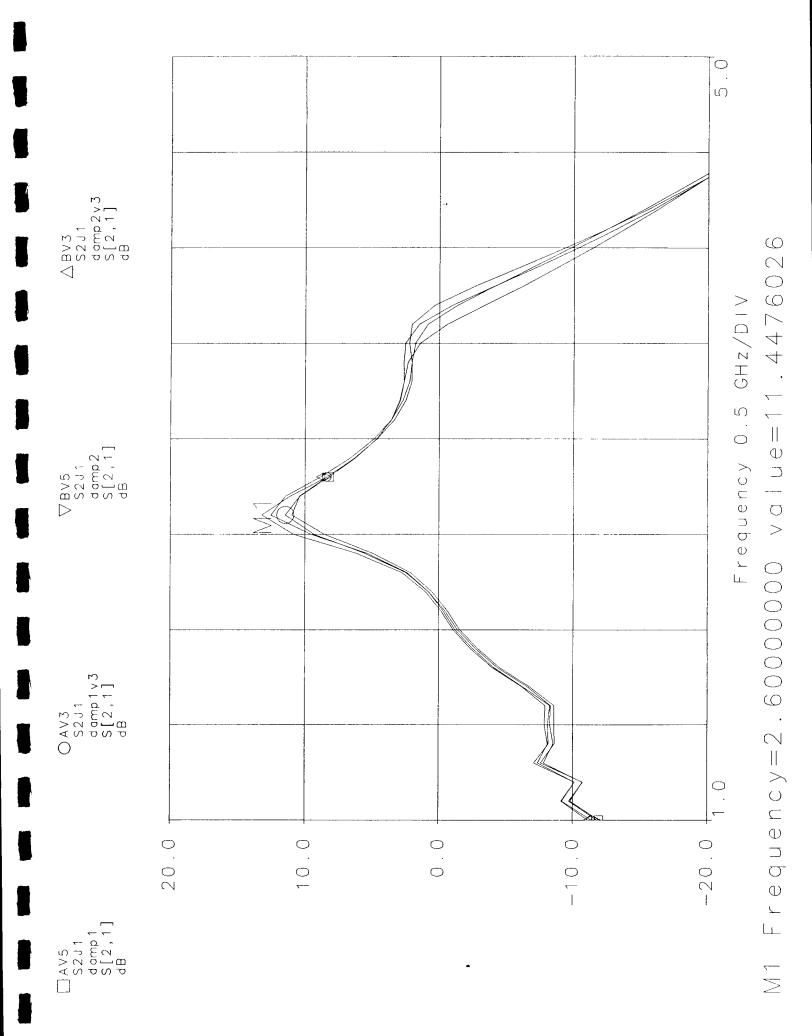
Summary: VCO oscillates with plenty of output power if the buffer amp is not used. Buffer amp needs to be redesigned as well as the inadvertant short in the oscillator tuning circuit. Driver Amp Testing Fall 96 MMIC Projects Mar 9, 1998 Bias Conditions: 5V 131 mA, 3V 130 mA chip #1, saved S-parms as DAMP1, and DAMP1V3

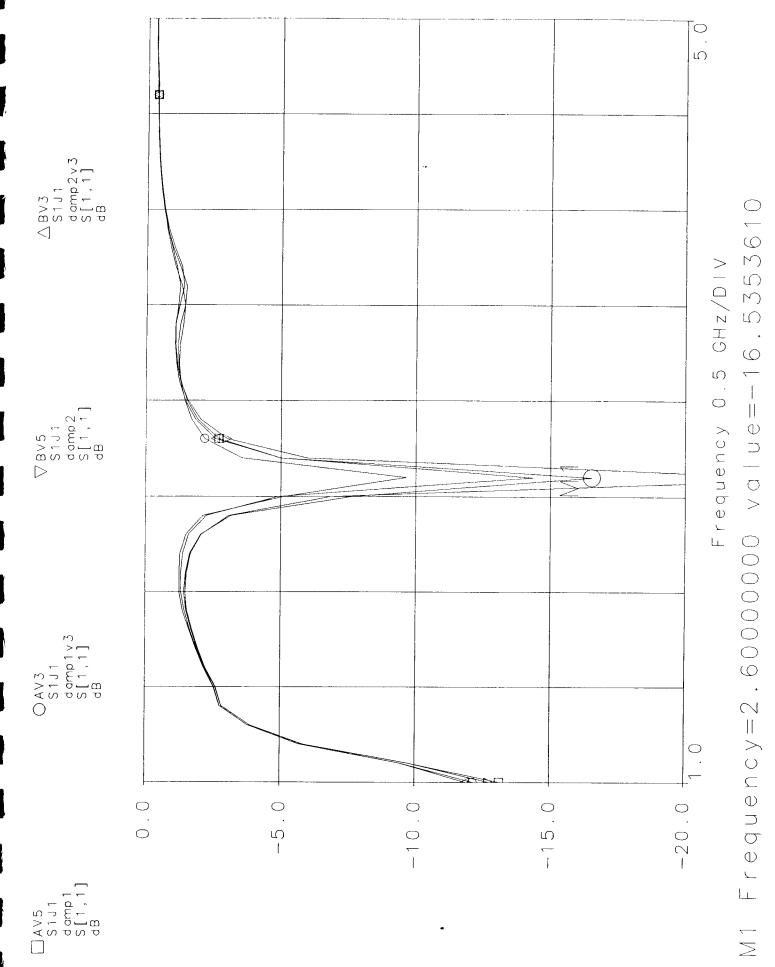
Bias Conditions: 5V 136 mA, 3V 136 mA chip #2, saved S-parms as DAMP2, and DAMP2V3

.

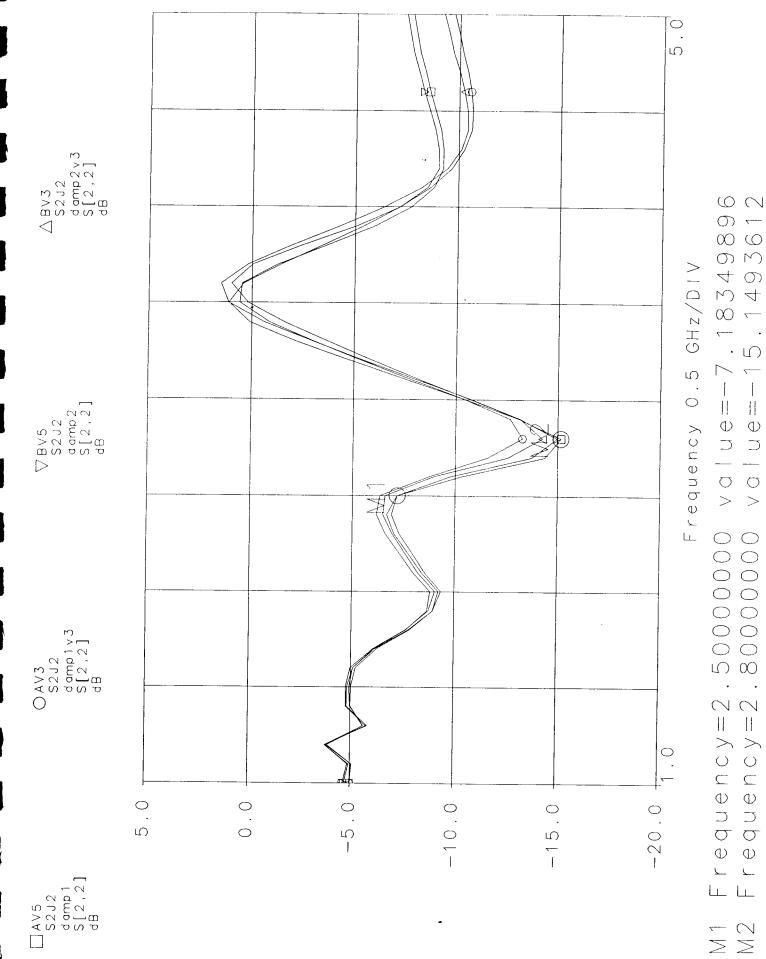
Part # 1	VD 5V	I(mA) 131	11.5 dB	S-parms DAMP1
1	4V	131	12.25 dB	
1	3V	130	13.5 dB	DAMP1V3
2	5V	136	10.9 dB	DAMP2
2	4V	137	11.4 dB	
2	3V	136	12.4 dB	DAMP2V3
3	5V	121	10.9 dB	
3	3V	119	12.4 dB	

Summary: Attached are the s-parameter plots. The part worked but was slightly high in frequency. Output power was not measured with this part but based on the power amp measurements from the same class/wafer it probably puts out something close to the students predictions. Not sure about the quality of the calibration for the S22 plot.





 \leq

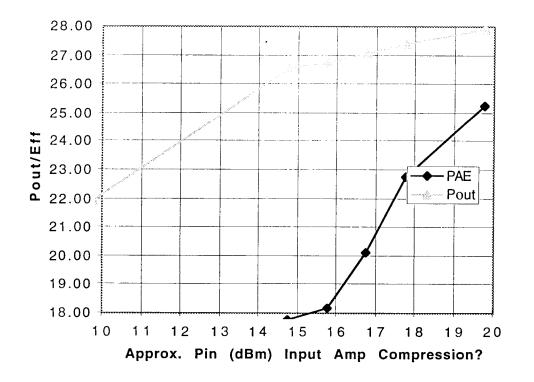


Power Amp1 Testing Fall 96 MMIC Projects (Robin Roddewig) Mar 9, 1998

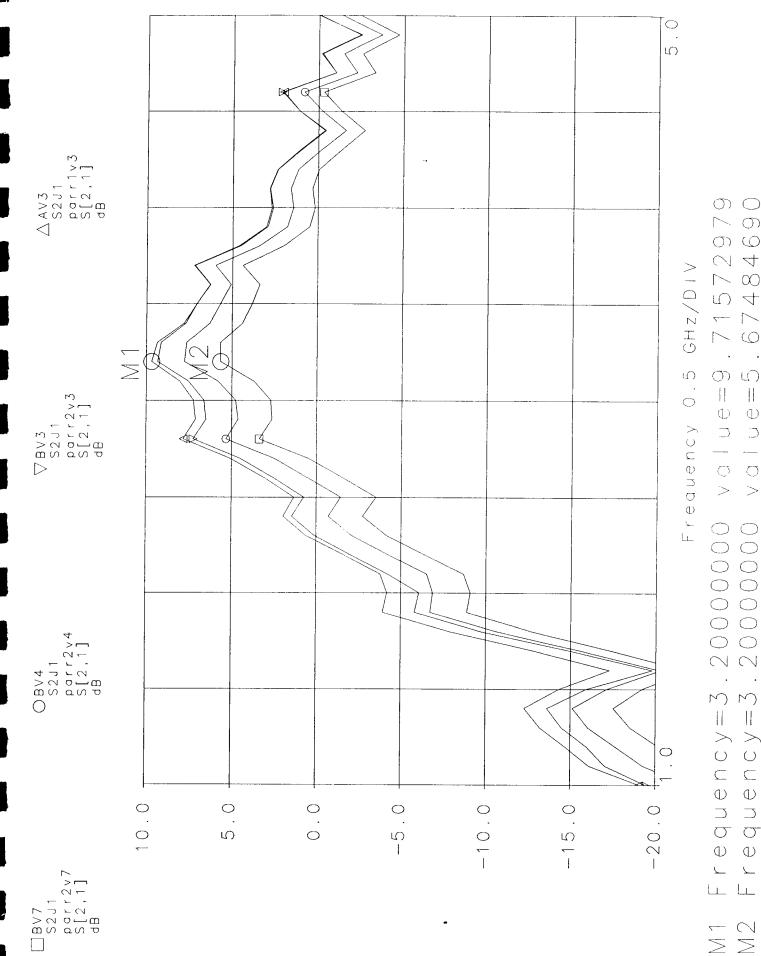
Part #	VD	I(mA)	S21	Gate	Gate (I) S-parms
1	2.5	360	9.1	-5V	12.5	· •
1	3.0	360	10.5	-5V	12.5	PARR1V3
2	2.5	330	9	-5V	12.5	
2	3.0	330	10.5	-5V	12.5	PARR2V3
2	4.0	346	8.7	-3V	7.5	PARR2V4
2	7.0	168	6.0	-5V	12.5	
2	7.0	293	6.4	-2V	5.0	PARR2V7

Summary: The part worked but was high in frequency. Small signal measurements improved when the die were attached to a large kovar heat sink for probe power measurements. However attached small signal measurements were before die attach (see plots). We had trouble getting sufficient drive power into the amp but we were successful in getting 1/2 Watt out of the part. Not sure what the compression level was but it appeared that we were limited in input power drive not output capability. Cal was at 2.44 Ghz, not 3!

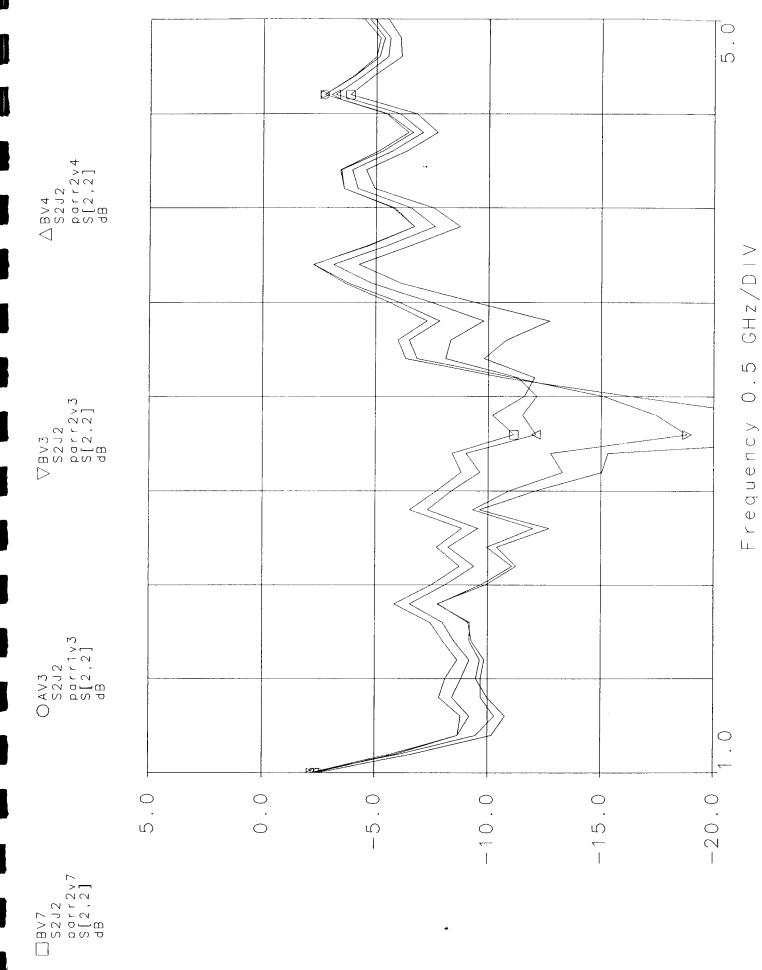
7.0 VD (a 402	mA; -5V gate r	network at 12.5	mA			1	1		1	
3.0 GHz]			1		
Pin		Pin(comprsd'	Pout	Pout (corr)	Gain	ID	POUT	PDC	DRAIN EFF	PIN	PAE EFF
	- 5	9.75	3.17	21.92	12.17	369	0.16	2.65	5.88	0.01	5.53
	0	14.75	7.83	26.58	11.83	333	0.45	2.39	19.01	0.03	17.77
	1	15.75	8	26.75	11.00	333	0.47	2.39	19.77	0.04	18.20
	2	16.75	8.33	27.08	10.33	320	0.51	2.30	22.18	0.05	20.12
	3	17.75	8.67	27.42	9.67	300	0.55	2.16	25.54	0.06	22.78
	5	<u>19.</u> 75	9.17	27.92	8.17	288	0.62	2.08	29.81	0.09	25.27



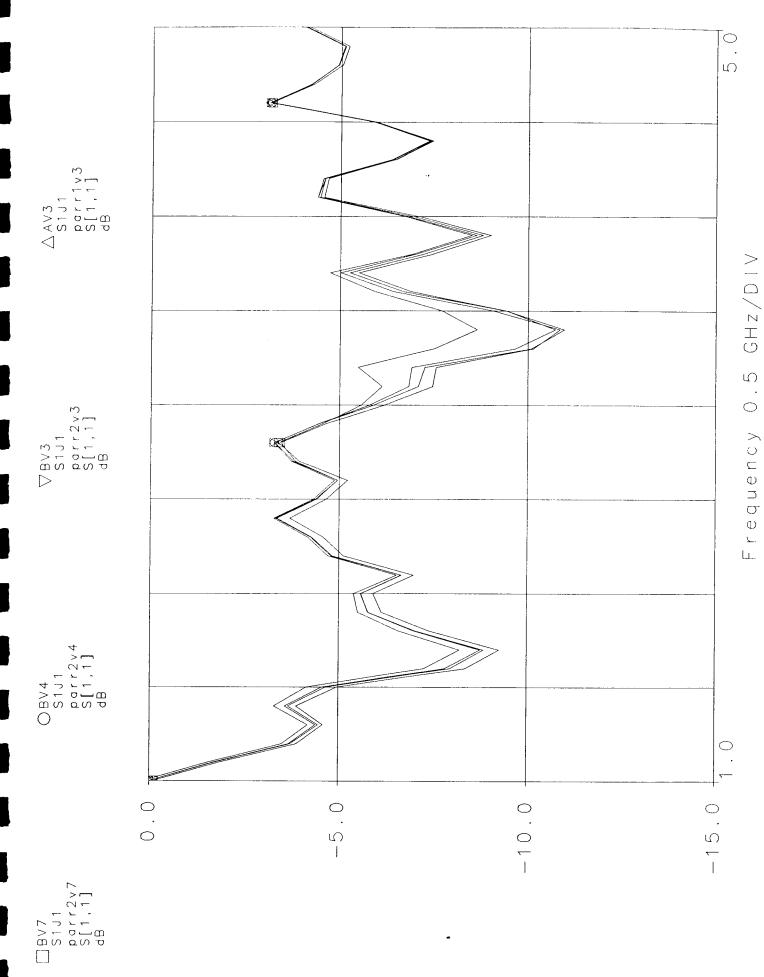
PAMP R.Roddewig VDD=7V 3.0 GHz



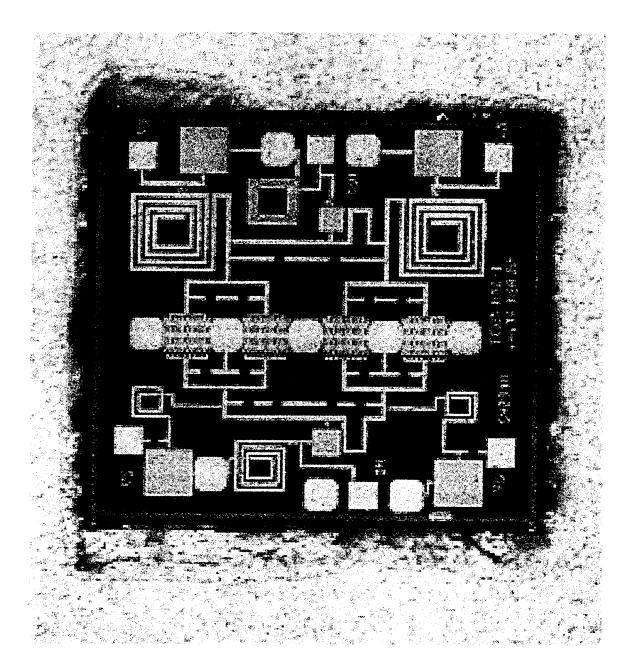
 \supset \mathcal{O}



.



ഹ . \bigcirc quency Φ ۲.

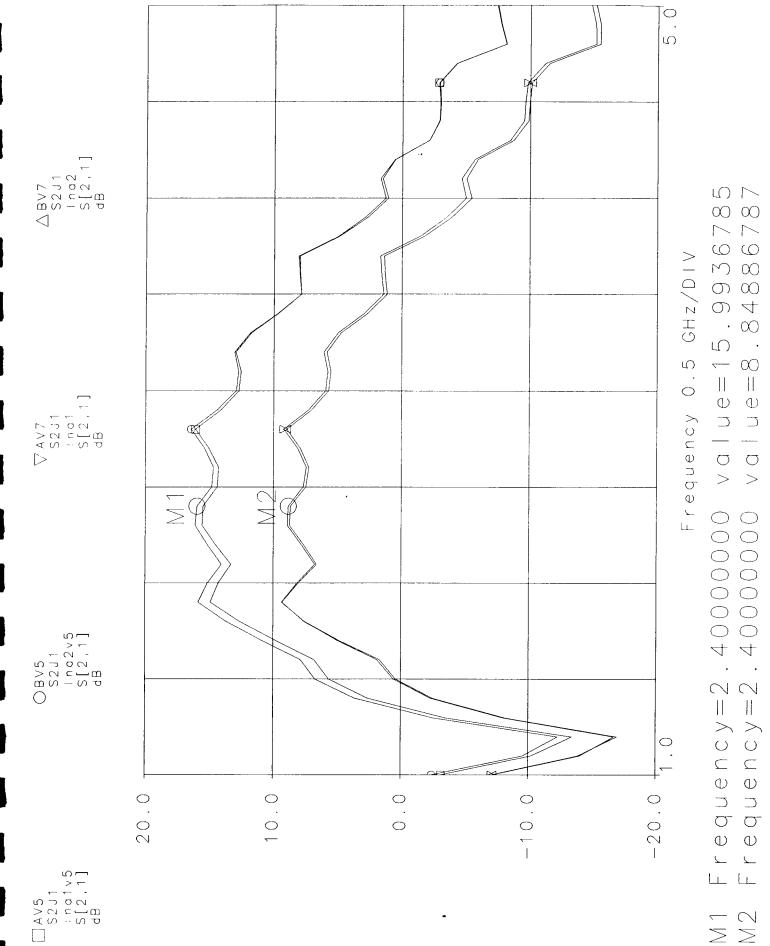


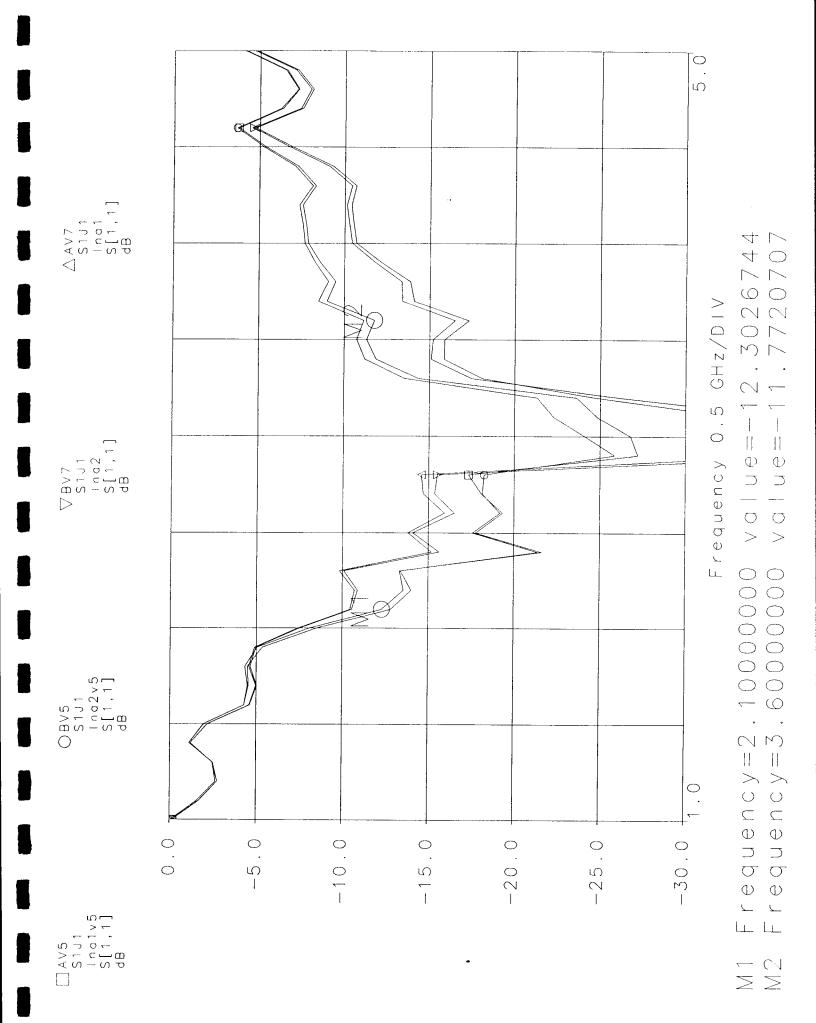
LNA Testing Fall 96 MMIC Projects Mar 9, 1998

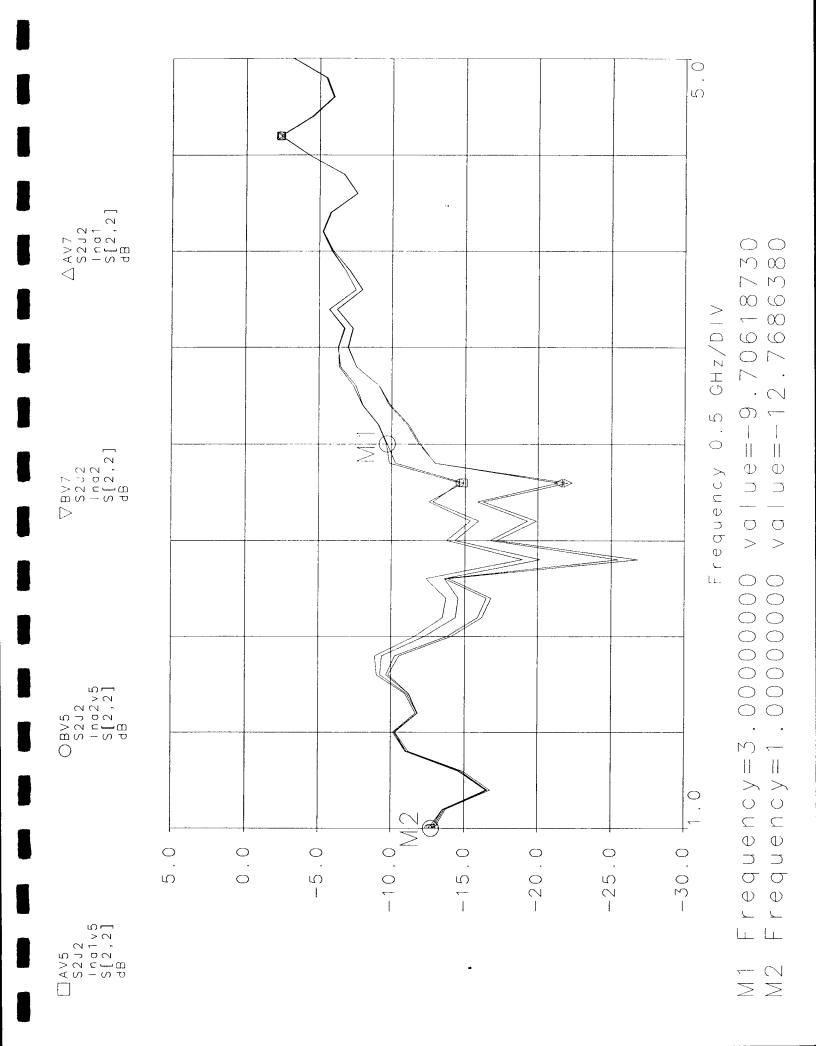
Part # 1 2 2	VD 7 5 7 5	I(mA) 49 16 49 16	S21 9 16 9 16	Gate -5V -5V -5V -5V	Gate (1 1.5 1.5 1.5 1.5	I) S-parms LNA1V7 LNA1V5 LNA2V7 LNA2V5
3/16						
Part # 1 1 1	VD 7 7 7	I(mA) 21 38 50	S21 18.3 14.1 10.6	Gate -6.5V -6.0V -5.5V	Gate (1 2.0 1.8 1.7	I) S-parms LNA7I21 LNA7I38 LNA7I50
2	, 7	20	18.6	-6.5V	2.0	LNA7I21B
2	7	35	16.0	-6.0V	1.8	LNA7I38B
2	7	48	11:6	-5.5V	1.7	LNA7I50B

Summary: The low noise amplifier was farely broadband as seen in the attached plots. However, it seemed to work better at 5V on the drain rather than the 7V as designed. It appeared that the single bias supply may have been supplying too much current. When we ran the parts at 7V but increased the gate voltage to reduce the drain current, the gain of the part went up several dB to the expected range. It was noted in measurements of an individual FET from that wafer run that the threshold voltage appeared to be around -1.8V to -1.9V rather than the -1.5V nominal. Noise measurements were not taken.

.







Power Amp2 Testing Fall 96 MMIC Projects (John Cavey) Mar 16, 1998 VG1, VG2 = -5.0V at 5.8mA per side, each supply is to 2 FETs

Part #	VD1,2	ID1,2(mA)	S21	S-parms
1	2.0	177,179	12	PÂJC2I35
1	3.0	184,182	12.3	PAJC3I37
1	4.0	186,186	12.2	PAJC4I37
1	5.0	176,147	11.7	PAJC5I33

Power Measurements at 4.0V VD? did not measure losses in wiring. Loss to Input 2.25 dB, Losses Added Output 9.75 dB Total = 12.0 dB, 2.5 dB in launches. Used Spectrum Analyzer to measure pout and signal generator to measure pin.

Pin	Pout	ID1, 2	Pin(adj)	Pout(adj)	Gain
-10	-11	183, 185	-12.25	-1.25	11.0?
0	0.8	182, 179	-2.25	10.6	12.9
10	11.5	170, 159	7.75	21.25	13.5
13.0	14.33	166, 146	10.75	24.1	13.4

Summary: The part was pretty much on frequency and we got 1/2 watt probed after attaching the die to a kovar to act as a heat sink. It was intended that the gate vias and drain bias were to be available at the top and bottom of the die but as this design was implemented the drain and gate bias at the top of the die supplies 2 of the FETs and the drain and gate bias pads at the bottom of the die supplies the other 2 FETs. Small signal measurements are attached. This device had more gain than the other power design and we calibrated at 2.44 Ghz so we were able to measure the gain compression. Unfortunately we were again limited by the input drive level of our test setup, not apparently by the part. It is just starting to compress when the 1/2 Watt level is achieved.

5.0 VD @ 326 mA; -5V gate network at 11.5 mA										
2.44 GHz	_		[
Pin	Pin (corr)	Pout	Pout (corr)	Gain	ID	POUT	PDC	DRAIN EFF	PIN	PAE EFF
0	9.75	3.83	22.58	12.83	326	0.18	1.69	10.74	0.01	10.18
3	12.41	6.5	25.25	12.84	325	0.33	1.68	19.91	0.02	18.88
5	13.91	7.83	26.58	12.67	323	0.45	1.67	27.21	0.02	
6	14.41	8.17	26.92	12.51	322	0.49	1.67	29.52	0.03	27.86

